Search Notes			

Application/Control No.	Applicant(s)/Patent und Reexamination	der
09/729,495	YUN ET AL.	
Examiner	Art Unit	
Thien D. Tran	2665	

SEARCHED			
Class	Subclass	Date	Examiner
370	209	7/24/2005	TT
	208	7/24/2005	TT
	203	7/24/2005	тт
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
370	209	7/24/2005	TT		
	208	7/24/2005	TT		
	203	7/24/2005	TT		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST (USPGPUB, USPAT, USOCR, EPO, DERWENT), 370/203, 208, 209, 320, 342, 441.	7/24/2005	ТТ
•		
Same as above	7/24/2005	тт
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